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	Туре	Hits	Search Text	DBs	Time Stamp
1	BRS	1198 8	history WITH (manufactur\$3 OR fabricat\$3 OR assembl\$3 OR produc\$4 OR construct\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 11:29
2	BRS	393	(history WITH (manufactur\$3 OR fabricat\$3 OR assembl\$3 OR produc\$4 OR construct\$3)) WITH quality	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	
3	BRS	100	((history WITH (manufactur\$3 OR fabricat\$3 OR assembl\$3 OR produc\$4 OR construct\$3)) WITH quality) WITH (memory OR db OR database OR data ADJ base OR table OR stor\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/06/17 11:31

09/654 052

	L#	Hits	Search Text	DBs	Time Stamp	Туре
1	L5	12	("5191313" "5225998" "5257206" "5311759" "5339257" "5351202" "5408405" "5423199" "5440478" "5442562" "5532941" "5815397" "5862054").PN.	USPAT	2004/06/17 17:14	BRS
2	L6	62	5440478.URPN.	USPAT	2004/06/17 17:17	BRS
3	L9	20	5787021.URPN.	USPAT	2004/06/17 17:22	BR

1	BRS	3	("5461570" "5706213" "5777876").PN.	USPAT	2004/06/14 14:54
<u> </u>	BRS	23	5777876.URPN. ·	USPAT	2004/06/14 15:19
3	BRS	3	5706213.URPN.	USPAT	2004/06/14 15:19
4	BRS	20	5461570.URPN.	USPAT	2004/06/14 15:19

	1	Document ID	Source	Issue Date		Current OR	Inventor	2
1		US 6633795 B1	USPAT	20031014	Manufactured article recycling system	700/213	Suzuki, Tatsuya et al.	☒
2		US 6522939 B1	USPAT	20030218	Computer system for quality control correlation	700/116	Strauch, Robert D. et al.	⊠
3		US 6459949 B1	USPAT	20021001	System and method for corrective action tracking in semiconductor processing	700/121	Black, Hang T. et al.	⋈
4		US 6061640 A	USPAT	20000509	Method of and apparatus for extracting abnormal factors in a processing operation	702/81	Tanaka, Masayuki et al.	☒
5		US 6036087 A	USPAT	20000314	Production history information apparatus and method using a bar code	235/375	Hong, Yu-Pyo et al.	⊠
6		US 6027022 A	USPAT	20000222	Quality control apparatus and method using a bar code data entry system	235/462. 01	Hong, Yu-Pyo	⊠
7		US 5596712 A	USPAT	19970121	Method and system for diagnosis and analysis of products troubles	714/26	Tsuyama, Tsutomu et al.	⊠
8		US 5166874 A	USPAT	19921124	Method and apparatus for production line fault management	700/79	Nomaru, Minoru et al.	⋈
9		JP 11065646 A	JPO	19990309	QUALITY DATA MANAGING DEVICE FOR SEMICONDUCTOR PRODUCT MANUFACTURING DEVICE AND METHOD THEREFOR		OKUDA, TATSUHIKO	Ø
10		JP 10091236 A	JPO	19980410	SYSTEM AND METHOD FOR SET HISTORY MANAGEMENT USING BAR CODE SYSTEM		HON, YUPYO et al.	⊠
11		JP 08090391 A	JPO	19960409	METHOD AND SYSTEM FOR CONTROLLING PRODUCT HISTORY	·	SUNAHARA, TORU et al.	⊠
12		JP 06060086 A	JPO	19940304	PRODUCT QUALITY CONTROL SYSTEM		SATOU, TADAMASA	☒
13		JP 05054549 A	JPO	19930305	STORAGE DEVICE AND DEVICE AND SYSTEM FOR RECORDING HISTORY INFORMATION BEFORE USE IN STORAGE DEVICE	-	ISHIMORI, YASUHIDE et al.	Ø
14		US 5761093 A	DERW ENT	19980602	Automatic defects amount predicting method used during manufacturing of new electronic assembly on production line - involves using quality forecasting engine to import enumerated bill of material and defect rate stored in historical database to calculate predicted number of defects		MULLEN, W B et al.	\boxtimes
15	Ø	US 5440478 A	USPAT	19950808	Process control method for improving manufacturing operations	700/109	Fisher, Gary et al.	
16		US 5787021 A	USPAT	19980728	Information system for production control	702/84	Samaha, Moustafa	☒

L# Hits			Search Text	DBs	DBs Time Stamp	
					2004/06/17	
1	L166	13078	707.clas.	USPAT	17:44	BRS
2	L167	36861	345.clas.	USPAT	2004/06/17 17:44	BRS
3	L168	19992	700.clas.	USPAT	2004/06/17 17:44	BRS
4	L169	21	L166 AND L167 AND L168	USPAT	2004/06/17 17:47	BRS
5	L170	199	L166 AND L168	USPAT	2004/06/17 17:48	BRS
6	L171	55	L170 AND quality	USPAT	2004/06/17 18:16	BRS
7	L172	4247	L168 AND quality	USPAT	2004/06/17 18:16	BRS
8	L173	63	L168 AND quality WITH (db OR database OR data ADJ base OR table) WITH (memory OR stor\$3)	USPAT	2004/06/17 18:17	BRS
9	L174	15	5245554.URPN.	USPAT	2004/06/17 18:24	BRS

	'	Document ID	Source	Issue Date	Title	Current OR	Inventor	2
1		US 6459949 B1	USPAT	20021001	System and method for corrective action tracking in semiconductor processing	700/121	Black, Hang T. et al.	
2		US 5806069 A	USPAT	19980908	Method and system of managing construction-related information and production-related	707/102	Wakiyama, Harumichi et al.	
3		US 6574522 B1	USPAT	20030603	System and method of collecting statistically analyzing and graphically displaying quality control data for a manufacturing	700/109	Douglas, Leonard Richard	
4		US 6522939 B1	USPAT	20030218	Computer system for quality control correlation	700/116	Strauch, Robert D. et al.	⊠
5		US 5461570 A	USPAT	19951024	Computer system for quality control correlations	700/110	Wang, Daniel T. et al.	⊠ ⊠
6		US 5452218 A	USPAT	19950919	System and method for determining quality analysis on fabrication and/or assembly design using shop capability data	700/110	Tucker, Marvin G. et al.	
7		US 5245554 A	USPAT	19930914	Integrated quality control method and system	702/185	Tsuyama, Tsutomu et al.	
8		US 6708130 B1	USPAT	20040316	Product quality information management system	702/82	Yamazaki, Yasuo et al.	⊠
9		US 6336078 B1	USPAT	20020101	Quality management of components	702/81	Sakayori, Masahiko et al.	\boxtimes
10		US 5940300 A	USPAT	19990817	Method and apparatus for analyzing a fabrication line	700/121	Ozaki, Hiroji	\boxtimes
11		US 5440478 A	USPAT	19950808	Process control method for improving manufacturing operations	700/109	Fisher, Gary et al.	
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